

## Digital Systems Testing And Testable Design Solutions

Summary Effective Unit Testing is written to show how to write good tests—tests that are concise and to the point, expressive, useful, and maintainable. Inspired by Roy Oshero's bestselling *The Art of Unit Testing*, this book focuses on tools and practices specific to the Java world. It introduces you to emerging techniques like behavior-driven development and specification by example, and shows you how to add robust practices into your toolkit. About Testing Test the components before you assemble them into a full application, and you'll get better software. For Java developers, there's now a decade of experience with well-crafted tests that anticipate problems, identify known and unknown dependencies in the code, and allow you to test components both in isolation and in the context of a full application. About this Book Effective Unit Testing teaches Java developers how to write unit tests that are concise, expressive, useful, and maintainable. Offering crisp explanations and easy-to-absorb examples, it introduces emerging techniques like behavior-driven development and specification by example. Programmers who are already unit testing will learn the current state of the art. Those who are new to the game will learn practices that will serve them well for the rest of their career. Purchase of the print book comes with an offer of a free PDF, ePub, and Kindle eBook from Manning. Also available is all code from the book. About the Author Lasse Koskela is a coach, trainer, consultant, and programmer. He hacks on open source projects, helps companies improve their productivity, and speaks frequently at conferences around the world. Lasse is the author of *Test Driven*, also published by Manning. What's Inside A thorough introduction to unit testing Choosing best-of-breed tools Writing tests using dynamic languages Efficient test automation Table of Contents PART 1 FOUNDATIONS The promise of good tests In search of good Test doubles PART 2 CATALOG Readability Maintainability Trustworthiness PART 3 DIVERSIONS Testable design Writing tests in other JVM languages Speeding up test execution

Defect oriented testing is expected to play a significant role in coming generations of technology. Smaller feature sizes and larger die sizes will make ICs more sensitive to defects that can not be modeled by traditional fault modeling approaches. Furthermore, with increased level of integration, an IC may contain diverse building blocks. Such blocks include, digital logic, PLAs, volatile and non-volatile memories, and analog interfaces. For such diverse building blocks, traditional fault modeling and test approaches will become increasingly inadequate. Defect oriented testing methods have come a long way from a mere interesting academic exercise to a hard industrial reality. Many factors have contributed to its industrial acceptance. Traditional approaches of testing modern integrated circuits (ICs) have been found to be inadequate in terms of quality and economics of test. In a globally competitive semiconductor market place, overall product quality and economics have become very important objectives. In addition, electronic systems are becoming increasingly complex and demand components of highest possible quality. Testing, in general and, defect oriented testing, in particular, help in realizing these objectives. *Defect Oriented Testing for CMOS Analog and Digital Circuits* is the first book to provide a complete overview of the subject. It is essential reading for all design and test professionals as well as researchers and students working in the field. `A strength of this book is its breadth. Types of designs

considered include analog and digital circuits, programmable logic arrays, and memories. Having a fault model does not automatically provide a test. Sometimes, design for testability hardware is necessary. Many design for testability ideas, supported by experimental evidence, are included.' ... from the Foreword by Vishwani D. Agrawal

This book is a self-contained introduction to all aspects of microelectronic (IC) testing. It includes the theory necessary for advanced students as well as reference to industrial practice and economics that will interest designers in industry. Chapters cover both digital circuit testing and the growing area of mixed circuits, used particularly in signal processing.

More than ever, mission-critical and business-critical applications depend on object-oriented (OO) software. Testing techniques tailored to the unique challenges of OO technology are necessary to achieve high reliability and quality. "Testing Object-Oriented Systems: Models, Patterns, and Tools" is an authoritative guide to designing and automating test suites for OO applications. This comprehensive book explains why testing must be model-based and provides in-depth coverage of techniques to develop testable models from state machines, combinational logic, and the Unified Modeling Language (UML). It introduces the test design pattern and presents 37 patterns that explain how to design responsibility-based test suites, how to tailor integration and regression testing for OO code, how to test reusable components and frameworks, and how to develop highly effective test suites from use cases. Effective testing must be automated and must leverage object technology. The author describes how to design and code specification-based assertions to offset testability losses due to inheritance and polymorphism. Fifteen micro-patterns present oracle strategies--practical solutions for one of the hardest problems in test design. Seventeen design patterns explain how to automate your test suites with a coherent OO test harness framework. The author provides thorough coverage of testing issues such as: The bug hazards of OO programming and differences from testing procedural code How to design responsibility-based tests for classes, clusters, and subsystems using class invariants, interface data flow models, hierarchic state machines, class associations, and scenario analysis How to support reuse by effective testing of abstract classes, generic classes, components, and frameworks How to choose an integration strategy that supports iterative and incremental development How to achieve comprehensive system testing with testable use cases How to choose a regression test approach How to develop expected test results and evaluate the post-test state of an object How to automate testing with assertions, OO test drivers, stubs, and test frameworks Real-world experience, world-class best practices, and the latest research in object-oriented testing are included. Practical examples illustrate test design and test automation for Ada 95, C++, Eiffel, Java, Objective-C, and Smalltalk. The UML is used throughout, but the test design patterns apply to systems developed with any OO language or methodology.

0201809389B04062001

Provides the only up-to-date source on the most recent advances in this often complex and fascinating topic. The only book to be entirely devoted to clocking Clocking has become one of the most important topics in the field of digital system design A "must have" book for advanced circuit engineers

Practical Problems in VLSI Physical Design Automation contains problems and solutions related to various well-known algorithms

used in VLSI physical design automation. Dr. Lim believes that the best way to learn new algorithms is to walk through a small example by hand. This knowledge will greatly help understand, analyze, and improve some of the well-known algorithms. The author has designed and taught a graduate-level course on physical CAD for VLSI at Georgia Tech. Over the years he has written his homework with such a focus and has maintained typeset version of the solutions.

Effective Software Testing explores fifty critically important best practices, pitfalls, and solutions. Gleaned from the author's extensive practical experience, these concrete items will enable quality assurance professionals and test managers to immediately enhance their understanding and skills, avoid costly mistakes, and implement a state-of-the-art testing program. This book places special emphasis on the integration of testing into all phases of the software development life cycle--from requirements definition to design and final coding. The fifty lessons provided here focus on the key aspects of software testing: test planning, design, documentation, execution, managing the testing team, unit testing, automated testing, nonfunctional testing, and more. You will learn to: Base testing efforts on a prioritized feature schedule Estimate test preparation and execution Define the testing team roles and responsibilities Design test procedures as soon as requirements are available Derive effective test cases from requirements Avoid constraints and detailed data elements in test procedures Make unit-test execution part of the build process Use logging to increase system testability Test automated test tools on an application prototype Automate regression tests whenever possible Avoid sole reliance on capture/playback Conduct performance testing with production-sized databases Tailor usability tests to the intended audience Isolate the test environment from the development environment Implement a defect tracking life cycle Throughout the book, numerous real-world case studies and concrete examples illustrate the successful application of these important principles and techniques. Effective Software Testing provides ready access to the expertise and advice of one of the world's foremost software quality and testing authorities. 0201794292B12032002

Modern electronics testing has a legacy of more than 40 years. The introduction of new technologies, especially nanometer technologies with 90nm or smaller geometry, has allowed the semiconductor industry to keep pace with the increased performance-capacity demands from consumers. As a result, semiconductor test costs have been growing steadily and typically amount to 40% of today's overall product cost. This book is a comprehensive guide to new VLSI Testing and Design-for-Testability techniques that will allow students, researchers, DFT practitioners, and VLSI designers to master quickly System-on-Chip Test architectures, for test debug and diagnosis of digital, memory, and analog/mixed-signal designs. Emphasizes VLSI Test principles and Design for Testability architectures, with numerous illustrations/examples. Most up-to-date coverage available, including Fault Tolerance, Low-Power Testing, Defect and Error Tolerance, Network-on-Chip (NOC) Testing, Software-Based Self-Testing, FPGA Testing, MEMS Testing, and System-In-Package (SIP) Testing, which are not yet available in any testing book. Covers the entire spectrum of VLSI testing and DFT architectures, from digital and analog, to memory circuits, and fault diagnosis and self-repair from digital to memory circuits. Discusses future nanotechnology test trends and challenges facing the nanometer design era; promising nanotechnology test techniques, including Quantum-Dots, Cellular Automata, Carbon-Nanotubes, and Hybrid

Semiconductor/Nanowire/Molecular Computing. Practical problems at the end of each chapter for students.

This book is the second of two volumes addressing the design challenges associated with new generations of semiconductor technology. The various chapters are compiled from tutorials presented at workshops in recent years by prominent authors from all over the world. Technology, productivity and quality are the main aspects under consideration to establish the major requirements for the design and test of upcoming systems on a chip.

The classic, landmark work on software testing The hardware and software of computing have changed markedly in the three decades since the first edition of *The Art of Software Testing*, but this book's powerful underlying analysis has stood the test of time. Whereas most books on software testing target particular development techniques, languages, or testing methods, *The Art of Software Testing, Third Edition* provides a brief but powerful and comprehensive presentation of time-proven software testing approaches. If your software development project is mission critical, this book is an investment that will pay for itself with the first bug you find. The new Third Edition explains how to apply the book's classic principles to today's hot topics including: Testing apps for iPhones, iPads, BlackBerrys, Androids, and other mobile devices Collaborative (user) programming and testing Testing for Internet applications, e-commerce, and agile programming environments Whether you're a student looking for a testing guide you'll use for the rest of your career, or an IT manager overseeing a software development team, *The Art of Software Testing, Third Edition* is an expensive book that will pay for itself many times over.

Your road map for meeting today's digital testing challenges Today, digital logic devices are common in products that impact public safety, including applications in transportation and human implants. Accurate testing has become more critical to reliability, safety, and the bottom line. Yet, as digital systems become more ubiquitous and complex, the challenge of testing them has become more difficult. As one development group designing a RISC stated, "the work required to . . . test a chip of this size approached the amount of effort required to design it." A valued reference for nearly two decades, *Digital Logic Testing and Simulation* has been significantly revised and updated for designers and test engineers who must meet this challenge. There is no single solution to the testing problem. Organized in an easy-to-follow, sequential format, this Second Edition familiarizes the reader with the many different strategies for testing and their applications, and assesses the strengths and weaknesses of the various approaches. The book reviews the building blocks of a successful testing strategy and guides the reader on choosing the best solution for a particular application. *Digital Logic Testing and Simulation, Second Edition* covers such key topics as: \* Binary Decision Diagrams (BDDs) and cycle-based simulation \* Tester architectures/Standard Test Interface Language (STIL) \* Practical algorithms written in a Hardware Design Language (HDL) \* Fault tolerance \* Behavioral Automatic Test Pattern Generation (ATPG) \* The

development of the Test Design Expert (TDX), the many obstacles encountered and lessons learned in creating this novel testing approach Up-to-date and comprehensive, Digital Logic Testing and Simulation is an important resource for anyone charged with pinpointing faulty products and assuring quality, safety, and profitability.

One skill that's essential for any professional JavaScript developer is the ability to write testable code. This book shows you what writing and maintaining testable JavaScript for the client- or server-side actually entails, whether you're creating a new application or rewriting legacy code. From methods to reduce code complexity to unit testing, code coverage, debugging, and automation, you'll learn a holistic approach for writing JavaScript code that you and your colleagues can easily fix and maintain going forward. Testing JavaScript code is complicated. This book helps experienced JavaScript developers simplify the process considerably. Get an overview of Agile, test-driven development, and behavior-driven development Use patterns from static languages and standards-based JavaScript to reduce code complexity Learn the advantages of event-based architectures, including modularity, loose coupling, and reusability Explore tools for writing and running unit tests at the functional and application level Generate code coverage to measure the scope and effectiveness of your tests Conduct integration, performance, and load testing, using Selenium or CasperJS Use tools for in-browser, Node.js, mobile, and production debugging Understand what, when, and how to automate your development processes

An Introduction to Logic Circuit Testing provides a detailed coverage of techniques for test generation and testable design of digital electronic circuits/systems. The material covered in the book should be sufficient for a course, or part of a course, in digital circuit testing for senior-level undergraduate and first-year graduate students in Electrical Engineering and Computer Science. The book will also be a valuable resource for engineers working in the industry. This book has four chapters. Chapter 1 deals with various types of faults that may occur in very large scale integration (VLSI)-based digital circuits. Chapter 2 introduces the major concepts of all test generation techniques such as redundancy, fault coverage, sensitization, and backtracking. Chapter 3 introduces the key concepts of testability, followed by some ad hoc design-for-testability rules that can be used to enhance testability of combinational circuits. Chapter 4 deals with test generation and response evaluation techniques used in BIST (built-in self-test) schemes for VLSI chips. Table of Contents: Introduction / Fault Detection in Logic Circuits / Design for Testability / Built-in Self-Test / References

This succinct book explains how you can apply the practices of Lean software development to dramatically increase productivity and quality. Based on techniques that revolutionized Japanese manufacturing, Lean principles are being applied successfully to product design, engineering, the supply chain, and now software development. With The Art of Lean Software Development, you'll learn how to adopt Lean practices one at a time rather than taking on the entire

methodology at once. As you master each practice, you'll see significant, measurable results. With this book, you will:

- Understand Lean's origins from Japanese industries and how it applies to software development
- Learn the Lean software development principles and the five most important practices in detail
- Distinguish between the Lean and Agile methodologies and understand their similarities and differences
- Determine which Lean principles you should adopt first, and how you can gradually incorporate more of the methodology into your process
- Review hands-on practices, including descriptions, benefits, trade-offs, and roadblocks
- Learn how to sell these principles to management

The Art of Lean Software Development is ideal for busy people who want to improve the development process but can't afford the disruption of a sudden and complete transformation. The Lean approach has been yielding dramatic results for decades, and with this book, you can make incremental changes that will produce immediate benefits. "This book presents Lean practices in a clear and concise manner so readers are motivated to make their software more reliable and less costly to maintain. I recommend it to anyone looking for an easy-to-follow guide to transform how the developer views the process of writing good software."-- Bryan Wells, Boeing Intelligence & Security Systems Mission System "If you're new to Lean software development and you're not quite sure where to start, this book will help get your development process going in the right direction, one step at a time."-- John McClenning, software development lead, Aclara

With Acceptance Test-Driven Development (ATDD), business customers, testers, and developers can collaborate to produce testable requirements that help them build higher quality software more rapidly. However, ATDD is still widely misunderstood by many practitioners. ATDD by Example is the first practical, entry-level, hands-on guide to implementing and successfully applying it. ATDD pioneer Markus Gärtner walks readers step by step through deriving the right systems from business users, and then implementing fully automated, functional tests that accurately reflect business requirements, are intelligible to stakeholders, and promote more effective development. Through two end-to-end case studies, Gärtner demonstrates how ATDD can be applied using diverse frameworks and languages. Each case study is accompanied by an extensive set of artifacts, including test automation classes, step definitions, and full sample implementations. These realistic examples illuminate ATDD's fundamental principles, show how ATDD fits into the broader development process, highlight tips from Gärtner's extensive experience, and identify crucial pitfalls to avoid. Readers will learn to Master the thought processes associated with successful ATDD implementation Use ATDD with Cucumber to describe software in ways businesspeople can understand Test web pages using ATDD tools Bring ATDD to Java with the FitNesse wiki-based acceptance test framework Use examples more effectively in Behavior-Driven Development (BDD) Specify software collaboratively through innovative workshops Implement more user-friendly and collaborative test automation Test more cleanly, listen to test results, and refactor tests for greater value If you're a tester,

analyst, developer, or project manager, this book offers a concrete foundation for achieving real benefits with ATDD now—and it will help you reap even more value as you gain experience.

This Textbook Provides A Comprehensive And Detailed Treatment Of Digital Systems Testing And Testable Design. It Covers Thoroughly Both The Fundamental Concepts And The Latest Advances In This Rapidly Changing Field, And Presents Only Theoretical Material That Supports Practical Applications. Successfully Used Worldwide, This Book Is An Invaluable Tool For Test Engineers, Asic And System Designers, And Cad Developers.

This handbook provides ready access to all of the major concepts, techniques, problems, and solutions in the emerging field of pseudorandom pattern testing. Until now, the literature in this area has been widely scattered, and published work, written by professionals in several disciplines, has treated notation and mathematics in ways that vary from source to source. This book opens with a clear description of the shortcomings of conventional testing as applied to complex digital circuits, reviewing by comparison the principles of design for testability of more advanced digital technology. Offers in-depth discussions of test sequence generation and response data compression, including pseudorandom sequence generators; the mathematics of shift-register sequences and their potential for built-in testing. Also details random and memory testing and the problems of assessing the efficiency of such tests, and the limitations and practical concerns of built-in testing.

DIGITAL SYSTEMS DESIGN USING VERILOG integrates coverage of logic design principles, Verilog as a hardware design language, and FPGA implementation to help electrical and computer engineering students master the process of designing and testing new hardware configurations. A Verilog equivalent of authors Roth and John's previous successful text using VHDL, this practical book presents Verilog constructs side-by-side with hardware, encouraging students to think in terms of desired hardware while writing synthesizable Verilog.

Following a review of the basic concepts of logic design, the authors introduce the basics of Verilog using simple combinational circuit examples, followed by models for simple sequential circuits. Subsequent chapters ask readers to tackle more and more complex designs. Important Notice: Media content referenced within the product description or the product text may not be available in the ebook version.

This book contains more than the IEEE Standard 1149.4. It also contains the thoughts of those who developed the standard. Adam Osseiran has edited the original writings of Brian Wilkins, Colin Maunder, Rod Tulloss, Steve Sunter, Mani Soma, Keith Lofstrom and John McDermid, all of whom have personally contributed to this standard. To preserve the original spirit, only minor changes were made, and the reader will sense a chapter-to-chapter variation in the style of expression. This may appear awkward to some, although I found the lack of monotonicity refreshing. A system consists of a specific organization of parts. The function of the system cannot be performed by an individual part or even a disorganized collection of the same parts. Testing has a system-like characteristic. Testing of a system does not follow directly from the testing of its parts, and a system built with testable parts can sometimes be impossible to test. Therefore, testability of the system must be organized. Some years ago, the IEEE published the boundary-scan Standard 1149.1. That Standard provided an architecture for digital VLSI chips. The chips designed with the 1149.1 architecture can be integrated into a testable system. However, many systems today contain both analog and digital chips. Even if all digital chips are compliant with the standard, the testability of a mixed-signal system cannot be guaranteed. The new Standard 1149.4, described in this book, extends the previous architecture to mixed-signal systems.

The modern electronic testing has a forty year history. Test professionals hold some fairly large conferences and numerous workshops, have a journal, and there are over one hundred books on testing. Still, a full course on testing is offered only at a few universities, mostly by

professors who have a research interest in this area. Apparently, most professors would not have taken a course on electronic testing when they were students. Other than the computer engineering curriculum being too crowded, the major reason cited for the absence of a course on electronic testing is the lack of a suitable textbook. For VLSI the foundation was provided by semiconductor device technology, circuit design, and electronic testing. In a computer engineering curriculum, therefore, it is necessary that foundations should be taught before applications. The field of VLSI has expanded to systems-on-a-chip, which include digital, memory, and mixed-signal subsystems. To our knowledge this is the first textbook to cover all three types of electronic circuits. We have written this textbook for an undergraduate "foundations" course on electronic testing. Obviously, it is too voluminous for a one-semester course and a teacher will have to select from the topics. We did not restrict such freedom because the selection may depend upon the individual expertise and interests. Besides, there is merit in having a larger book that will retain its usefulness for the owner even after the completion of the course. With equal tenacity, we address the needs of three other groups of readers.

Using the book and the software provided with it, the reader can build his/her own tester arrangement to investigate key aspects of analog-, digital- and mixed system circuits. Plan of attack based on traditional testing, circuit design and circuit manufacture allows the reader to appreciate a testing regime from the point of view of all the participating interests. Worked examples based on theoretical bookwork, practical experimentation and simulation exercises teach the reader how to test circuits thoroughly and effectively.

In the early days of digital design, we were concerned with the logical correctness of circuits. We knew that if we slowed down the clock signal sufficiently, the circuit would function correctly. With improvements in the semiconductor process technology, our expectations on speed have soared. A frequently asked question in the last decade has been how fast can the clock run. This puts significant demands on timing analysis and delay testing. Fueled by the above events, a tremendous growth has occurred in the research on delay testing. Recent work includes fault models, algorithms for test generation and fault simulation, and methods for design and synthesis for testability. The authors of this book, Angela Krstic and Tim Cheng, have personally contributed to this research. Now they do an even greater service to the profession by collecting the work of a large number of researchers. In addition to expounding such a great deal of information, they have delivered it with utmost clarity. To further the reader's understanding many key concepts are illustrated by simple examples. The basic ideas of delay testing have reached a level of maturity that makes them suitable for practice. In that sense, this book is the best x DELAY FAULT TESTING FOR VLSI CIRCUITS available guide for an engineer designing or testing VLSI systems. Techniques for path delay testing and for use of slower test equipment to test high-speed circuits are of particular interest.

This book is about digital system testing and testable design. The concepts of testing and testability are treated together with digital design practices and methodologies. The book uses Verilog models and testbenches for implementing and explaining fault simulation and test generation algorithms. Extensive use of Verilog and Verilog PLI for test applications is what distinguishes this book from other test and testability books. Verilog eliminates ambiguities in test algorithms and BIST and DFT hardware architectures, and it clearly describes the architecture of the testability hardware and its test sessions. Describing many of the on-chip decompression algorithms in Verilog helps to evaluate these algorithms in terms of hardware overhead and timing, and thus feasibility of using them for System-on-Chip designs. Extensive use of testbenches and testbench development techniques is another unique feature of this book. Using PLI in developing testbenches and virtual testers provides a powerful programming tool, interfaced with hardware described in Verilog. This mixed hardware/software environment facilitates description of complex test programs and test strategies.

Device testing represents the single largest manufacturing expense in the semiconductor industry, costing over \$40 billion a year. The most comprehensive and wide ranging book of its kind, *Testing of Digital Systems* covers everything you need to know about this vitally important subject. Starting right from the basics, the authors take the reader through automatic test pattern generation, design for testability and built-in self-test of digital circuits before moving on to more advanced topics such as IDDQ testing, functional testing, delay fault testing, memory testing, and fault diagnosis. The book includes detailed treatment of the latest techniques including test generation for various fault models, discussion of testing techniques at different levels of integrated circuit hierarchy and a chapter on system-on-a-chip test synthesis. Written for students and engineers, it is both an excellent senior/graduate level textbook and a valuable reference.

### Digital Systems Testing and Testable Design

This is the eBook of the printed book and may not include any media, website access codes, or print supplements that may come packaged with the bound book. For all courses in digital electronics, from introductory through advanced. Like previous editions, this text will be used widely in technology classes ranging from high schools and two-year programs to four-year engineering, engineering technology, and computer science programs. Take a journey in *Digital Systems* from novice to expert. Written for all courses in digital electronics—from introductory to advanced, from high school to two- and four-year college programs—this Twelfth Edition of *Digital Systems* thoroughly prepares students for the study of digital systems and computer and microcontroller hardware. The text begins with the basics of digital systems, including the AHDL hardware description language, then gradually progresses to increasingly challenging topics, including the more complex VHDL. The text is comprehensive yet highly readable, clearly introducing the purpose and fundamentals of each topic before delving into more technical descriptions. It is also definition-focused, with new terms listed in each chapter and defined in a glossary. This Twelfth Edition has been thoroughly revised and updated with new material on section-level learning outcomes, Quadrature Shaft Encoders used to obtain absolute shaft positions, troubleshooting prototype circuits using systematic fault isolation techniques, Time Division Multiplexing, expanded discussion of VHDL data objects and more!

### Hardware -- Logic Design.

This updated printing of the leading text and reference in digital systems testing and testable design provides comprehensive, state-of-the-art coverage of the field. Included are extensive discussions of test generation, fault modeling for classic and new technologies, simulation, fault simulation, design for testability, built-in self-test, and diagnosis. Complete with numerous problems, this book is a must-have for test engineers, ASIC and system designers, and CAD developers, and advanced engineering students will find this book an invaluable tool to keep current with recent changes in the field.

The book constitutes the refereed proceedings of the 9th International Conference on Verification, Model Checking, and Abstract Interpretation, VMCAI 2007, held in San Francisco, USA, in January 2008. The 21 revised full papers presented together with 2 invited lectures and 2 invited tutorials were carefully reviewed and selected from a total of over 60 submissions. The papers feature current research from the communities of verification, program certification, model checking, debugging techniques,

abstract interpretation, abstract domains, static analysis, cross-fertilization, and advancement of hybrid methods.

This book provides broad and comprehensive coverage of the entire EDA flow. EDA/VLSI practitioners and researchers in need of fluency in an "adjacent" field will find this an invaluable reference to the basic EDA concepts, principles, data structures, algorithms, and architectures for the design, verification, and test of VLSI circuits. Anyone who needs to learn the concepts, principles, data structures, algorithms, and architectures of the EDA flow will benefit from this book. Covers complete spectrum of the EDA flow, from ESL design modeling to logic/test synthesis, verification, physical design, and test - helps EDA newcomers to get "up-and-running" quickly Includes comprehensive coverage of EDA concepts, principles, data structures, algorithms, and architectures - helps all readers improve their VLSI design competence Contains latest advancements not yet available in other books, including Test compression, ESL design modeling, large-scale floorplanning, placement, routing, synthesis of clock and power/ground networks - helps readers to design/develop testable chips or products Includes industry best-practices wherever appropriate in most chapters - helps readers avoid costly mistakes

How do successful agile teams deliver bug-free, maintainable software—iteration after iteration? The answer is: By seamlessly combining development and testing. On such teams, the developers write testable code that enables them to verify it using various types of automated tests. This approach keeps regressions at bay and prevents “testing crunches”—which otherwise may occur near the end of an iteration—from ever happening. Writing testable code, however, is often difficult, because it requires knowledge and skills that cut across multiple disciplines. In *Developer Testing*, leading test expert and mentor Alexander Tarlinder presents concise, focused guidance for making new and legacy code far more testable. Tarlinder helps you answer questions like: When have I tested this enough? How many tests do I need to write? What should my tests verify? You’ll learn how to design for testability and utilize techniques like refactoring, dependency breaking, unit testing, data-driven testing, and test-driven development to achieve the highest possible confidence in your software. Through practical examples in Java, C#, Groovy, and Ruby, you’ll discover what works—and what doesn’t. You can quickly begin using Tarlinder’s technology-agnostic insights with most languages and toolsets while not getting buried in specialist details. The author helps you adapt your current programming style for testability, make a testing mindset “second nature,” improve your code, and enrich your day-to-day experience as a software professional. With this guide, you will Understand the discipline and vocabulary of testing from the developer’s standpoint Base developer tests on well-established testing techniques and best practices Recognize code constructs that impact testability Effectively name, organize, and execute unit tests Master the essentials of classic and “mockist-style” TDD Leverage test doubles with or without mocking frameworks Capture the benefits of programming by contract, even without runtime support for contracts Take control of dependencies between classes, components, layers, and tiers Handle combinatorial explosions of test cases, or scenarios requiring many similar tests Manage code duplication when it can’t be eliminated Actively maintain and improve your test suites Perform more advanced tests at the integration, system, and end-to-end levels Develop an understanding for how the organizational context influences quality assurance Establish well-balanced and effective testing strategies suitable for

agile teams

A superior primer on software testing and quality assurance, from integration to execution and automation This important new work fills the pressing need for a user-friendly text that aims to provide software engineers, software quality professionals, software developers, and students with the fundamental developments in testing theory and common testing practices. Software Testing and Quality Assurance: Theory and Practice equips readers with a solid understanding of: Practices that support the production of quality software Software testing techniques Life-cycle models for requirements, defects, test cases, and test results Process models for units, integration, system, and acceptance testing How to build test teams, including recruiting and retaining test engineers Quality Models, Capability Maturity Model, Testing Maturity Model, and Test Process Improvement Model Expertly balancing theory with practice, and complemented with an abundance of pedagogical tools, including test questions, examples, teaching suggestions, and chapter summaries, this book is a valuable, self-contained tool for professionals and an ideal introductory text for courses in software testing, quality assurance, and software engineering.

Is software quality testing really effective or just a waste of time? The skeptics conclude that it is an exercise in futility to try to measure the reliability and safety of these complex systems under all critical circumstances. They contend that quality assurance comes only through a strict adherence to rigorous development process models. In this groundbreaking book, Michael Friedman and Jeffrey Voas dispel that myth. They demonstrate that extremely accurate, cost-effective software quality testing can now be a reality, thanks to powerful new analytical tools. Central to the approach outlined in Software Assessment is a sophisticated assessment optimization technique called testability analysis. Pioneered at the College of William and Mary and NASA by Jeffrey Voas, testability analysis predicts the likelihood that latent bugs will be detected during testing. Drawing upon their experiences working on various high-profile projects—including air traffic control systems, an automated high-speed train-control system, and a CASE-generated autopilot system—they describe how testability analysis is used to determine which tests work and which do not; how much testing should be done on a given program; which areas of a program (modules, lines of code, etc.) are the most testable and which are the least testable; and how to allocate precious resources. The authors also describe original techniques for designing and coding programs to maximize their testability and a new method of generating test cases to support testing and testability analysis. Software Assessment offers a balanced presentation of theory and practice and is designed to function as either (continued on back flap) (continued from front flap) graduate-level text or professional reference. Featuring exhaustive coverage of the theoretical foundations of reliability, safety, and testability, it uses real-world examples, illustrations, and clear descriptions to explore all of the latest techniques for assessing those qualities. Information technology and the software that makes it possible are vital aspects of our economic, political, and cultural lives. Software Assessment provides powerful new tools for assessing and enhancing the safety, reliability, and testability of these crucial resources. Software Assessment Breakthrough tools and techniques that make accurate, cost-effective software quality testing a reality Written by two of the most prominent figures in the field of software quality testing, Software Assessment arms software designers and developers with cutting-edge

tools and techniques for measuring and enhancing the safety, reliability, and testability of the programs they produce. Drawing upon their experiences working on major software projects at NASA and other agencies for which software quality is literally a matter of life and death, Michael Friedman and Jeffrey Voas show you how to: Use powerful testability tools and techniques to optimize the testing process Execute programs to perform automated quality testing Design and code programs for maximum testability Generate test cases to support testing and testability analysis And much more Cover Design/Illustration: Robin Lee Malik

"This book explores different applications in V & V that spawn many areas of software development -including real time applications- where V & V techniques are required, providing in all cases examples of the applications"--Provided by publisher. This textbook provides a comprehensive and detailed treatment of digital systems testing and testable design. It covers thoroughly both the fundamental concepts and the latest advances in this rapidly changing field, and presents only theoretical material that supports practical applications. Successfully used worldwide, this book is an invaluable tool for test engineers, ASIC and system designers, and CAD developers.

This book is a comprehensive guide to new DFT methods that will show the readers how to design a testable and quality product, drive down test cost, improve product quality and yield, and speed up time-to-market and time-to-volume. Most up-to-date coverage of design for testability. Coverage of industry practices commonly found in commercial DFT tools but not discussed in other books. Numerous, practical examples in each chapter illustrating basic VLSI test principles and DFT architectures. CD-ROM contains: Canned HEAT v.2.0 -- Holodeck Lite v. 1.0.

This key text addresses the complex computer chips of tomorrow which will consist of several layers of metal interconnect, making the interconnect within a chip or a multichip module a three dimensional problem. You'll find an insightful approach to the algorithmic, cell design issues in chip and MCM routing with an emphasis on techniques for eliminating routing area.

This book introduces several novel approaches to pave the way for the next generation of integrated circuits, which can be successfully and reliably integrated, even in safety-critical applications. The authors describe new measures to address the rising challenges in the field of design for testability, debug, and reliability, as strictly required for state-of-the-art circuit designs. In particular, this book combines formal techniques, such as the Satisfiability (SAT) problem and the Bounded Model Checking (BMC), to address the arising challenges concerning the increase in test data volume, as well as test application time and the required reliability. All methods are discussed in detail and evaluated extensively, while considering industry-relevant benchmark candidates. All measures have been integrated into a common framework, which implements standardized software/hardware interfaces.

Get more out of your legacy systems: more performance, functionality, reliability, and manageability Is your code easy to change? Can you get nearly instantaneous feedback when you do change it? Do you understand it? If the answer to any of these questions is no, you have legacy code, and it is draining time and money away from your development efforts. In this book, Michael Feathers

offers start-to-finish strategies for working more effectively with large, untested legacy code bases. This book draws on material Michael created for his renowned Object Mentor seminars: techniques Michael has used in mentoring to help hundreds of developers, technical managers, and testers bring their legacy systems under control. The topics covered include Understanding the mechanics of software change: adding features, fixing bugs, improving design, optimizing performance Getting legacy code into a test harness Writing tests that protect you against introducing new problems Techniques that can be used with any language or platform—with examples in Java, C++, C, and C# Accurately identifying where code changes need to be made Coping with legacy systems that aren't object-oriented Handling applications that don't seem to have any structure This book also includes a catalog of twenty-four dependency-breaking techniques that help you work with program elements in isolation and make safer changes.

[Copyright: 1245e6811c85e67af053f80f385cefac](#)